

SIMTEK6349

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of
Chihiro, Araki

App. No.: 10/063,869

Filed: May 21, 2002

Conf. No.: 2434

Title: INSPECTION METHOD AND
INSPECTION APPARATUS FOR
SEMICONDUCTOR CIRCUIT

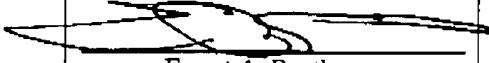
Examiner: T. Nguyen

Art Unit: 2829

Commissioner for Patents
Arlington, VA 22313-1450

I hereby certify that this correspondence and all
marked attachments are being deposited with
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May 5, 2003


Ernest A. Beutler
Reg. No. 19901

AMENDMENT

Dear Sir:

In response to the Office Action, dated February 3, 2003, please amend this application, as follows: